

3653

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: R.B. Darling et al. Attorney Docket No.: UWOTL116278
Application No.: 09/744,360 Group Art Unit: 3653
Filed: January 22, 2001 Examiner: T.N. Nguyen
Title: CHARGED PARTICLE BEAM DETECTION SYSTEM

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

August 15, 2003

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TO THE COMMISSIONER FOR PATENTS:

Applicants are aware of the information listed in the attached form that may be material to the prosecution of the above-identified patent application.

1. X Copies of the listed patents, publications, and other information are enclosed for the Examiner's use.
2. X Pursuant to 37 C.F.R. § 1.97(b), this Information Disclosure Statement is being filed within three months of the filing date of the national application (other than a CPA), within three months of the date of entry of the national stage as set forth in 37 C.F.R. § 1.491 in an international application, before the mailing date of a first Office Action on the merits, or before the mailing date of a first Office Action after the filing of an RCE.

Respectfully submitted,

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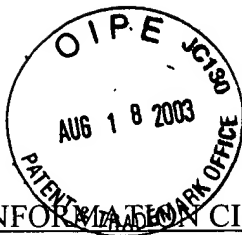
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I hereby certify that this correspondence is being deposited with the U.S. Postal Service in a sealed envelope as first class mail with postage thereon fully prepaid and addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the below date.

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INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL TO THE
PROSECUTION OF THE SUBJECT APPLICATION

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U.S. PATENT DOCUMENTS

*Examiner Cite	Kind	Date	
Initials No. Document No. Code (mm/dd/yyyy) Name			
U5	4,724,324	02/09/1988	Liebert

FOREIGN PATENT DOCUMENTS

*Examiner Cite	Kind	Publication Date	Country	English Abstract Translation Provided Provided
Initial No. Document No. Code (mm/dd/yyyy)				

NONE

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

*Examiner Cite	
Initial No.	
O1	Natsuaki, N., et al., "Spatial Dose Uniformity Monitor for Electrically Scanned Ion Beam," <i>Rev. Sci. Instrum.</i> 49(9):1300-1304, September 1978.
O2	O'Morain, C., et al., "Large-Diameter Plasma Profile Monitoring System Using Faraday Cup and Langmuir Probe Arrays," <i>Meas. Sci. Technol.</i> 4:1484-1488, December 1993.
O3	Scheidemann, A.A. et al., "Linear Dispersion Mass Spectrometer," <i>Proceedings of the 47th American Society for Mass Spectrometry Conference on Mass Spectrometry and Allied Topics</i> , Dallas, Texas, June 1999.

Examiner

Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

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